3M[™] Wiremount Sockets IDC Connector 3000 Series

Product Specification 78-5102-0014-0

Released: 09-27-11



Table of Contents

Sectio	n	Page
1.	Scope	3
2.	3M Customer Documents	3
3.	Performance and Test Descriptions	3
4.	Requirements Overview	3
5.	Electrical	4
6.	Mechanical	4
7.	Physical	4
8.	Environmental	5
9.	Test Sequence	5
10.	Figures	6
11.	Agency Listings	7

nportant Notice	8
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1. Scope

This document summarizes test methods, test conditions and product performance requirements for the 3M Wiremount Sockets 3000 Series. Listings of materials, finishes, test conditions, and test standards are included in this specification. In the event of conflict between this specification and any documents listed below, the listed documentation supersedes this specification.

2. 3M Documents

78-5100-0718-6 TS-0718, Technical Data Sheet for 3000 Series Wiremount Socket
78-5100-0719-4 TS-0719, Technical Data Sheet for 3000 Series Wiremount Socket, Preassembled
34-7027-4814-5 3443-94 3M[™] Locator Plate Instructions

3. Performance and Test Description

Unless otherwise specified, all tests shall be performed on 3000 Series Sockets with 30μ " of gold mated to $3M^{TM}$ Headers 2500 Series using $3M^{TM}$ Cable 3365/60 and 3801/60 at ambient environmental conditions per EIA-364. Unless otherwise specified, all values and limits are typical of those obtained by qualification testing of the subject product. All specifications are subject to revision and change without notice from 3M.

4. Requirements Overview

4.1 Ratings

Dielectric Withstanding Voltage: 500 VAC_{RMS} at sea level

Current: (EIA-364-070 method 2, 30°C maximum temperature rise.) 1 Line 6* Lines All Lines

	1 Line	6° Lines	All Line
28 AWG	4.50	1.75	1.00
26 AWG	4.75	2.00	1.00
Temperature: -55	°C to +105°C	:	
Inculation Perieta	$nco: >1 \times 10^9$		\sim

Insulation Resistance: >1 $x10^{9}\Omega$ at 500 VDC

4.2 Materials

Insulation: Glass Filled Polyester PBT Strain Relief: Plastic, Metal Contact: Copper Alloy

4.3 Finishes

Plating:

Nickel: 50 - 150 μ inches, ASTM B689-97, SAE AMS-QQ-N-290 Gold - Contact: 30 μ inches, MIL-G-45204 Type II, Grade C

4.4 Regulatory Compliance

See the Regulatory Information Appendix (RIA) in the "RoHS compliance" section of **www.3Mconnectors.com** for compliance information. See customer drawings for regulatory specifics on each connector.

*Lines are adjacent in 2x3 configuration

5. Electrical

Description or Parameter	Values & Limits		Units	Requirement or Conditions	Test Standard or Method	
Dielectric Withstanding Voltage		00	VAC _{RMS}	Measured between adjacent and opposing contacts. No disruptive discharge during 1 minute duration. Sea level with 70% relative humidity.	EIA-364-20B	
Current Rating	28 AWG 4.50	26 AWG 4.75	Amperes	Wire gage. 1 line driven, 30°C temp, rise, 20% derated.	EIA-364-70A	
	1.75	2.00 1.00	-	6 line driven. 30°C temp. rise. 20% derated. All line driven. 30°C temp. rise. 20% derated.		
Low Level Connection Resistance <10		Milliohms	10 milliohm maximum ΔR contact resistance per mated interface throughout testing.	EIA-364-23A		
Insulation Resistance >1x10 ⁹		×10 ⁹	Ohms	Measured between adjacent and opposing contacts. 500 VDC for 1 minute duration.	EIA-364-21 B	

6. Mechanical

Description or Parameter	Values & Limits	Units	Requirement or Conditions	Test Standard or Method
Header Pin Retention / Contact	>900	g	Force / contact required to remove pin from header body.	EIA-364-29B
Vibration	≤10	ns	Mated connectors shall exhibit no discontinuities greater than specified. 10 milliohm maximum ∆R contact resistance per mated interface throughout testing.	EIA-364-28D Condition III
Physical Shock	≤10	ns	Mated connectors shall exhibit no discontinuities greater than specified. 10 milliohm maximum ∆R contact resistance per mated interface throughout testing.	EIA-364-27B Test Cond. A
Mating Force / Contact	0.50 max	lbs	Mated to a .025" square pin. (Insertion Force)	EIA-364-13B
Unmating Force / Contact	0.075 min	lbs	Mated to a .025" square pin. (Withdrawl Force)	EIA-364-13B
Contact Wiper Normal Force	≥100	g	Displacement equivalent to mating with a .0245" square pin. Test at end of sequence C.	EIA-364-04
Durability (with Environmental)	50 (30 μ")	Mating cycles	10 milliohm maximum $\triangle R$ contact resistance per mated interface throughout testing.	EIA-364-09C

7. Physical

Description or Parameter	Values & Limits	Units	Requirement or Conditions	Test Standard or Method
Visual	NA	NA	No defects such as deformation, blister, damage, crack, etc.	EIA-364-18A
(Metallic Coating) Adhesion	NA	NA	No cracking, flaking.	MIL-G-45204 Section 4.5.2
Plating thickness Nickel Gold Tin	50-150 30 100-300	μ"	Average of random measurements from any 3 lots.	EIA-364-48
Header Solderability, Lead-Free Dip Test	>95	Percent	Coverage of solderable area.	EIA-364-52 Category 3

8. Environmental

Description or Parameter	Values & Limits	Units	Requirement or Conditions	Test Standard or Method
Temperature Life (Thermal Aging)	Temperature Life (Thermal Aging)1051091000 hours. No physical abnormalities . 10 milliohm maximum ∆R contact resistance per mated interface throughout testing.		EIA-364-17A Method A Condition 4	
Humidity	10	24 hr cycles	25-65 C / 90-98%RH with -10 degree C subcycles. 10 milliohm maximum ∆R contact resistance per mated interface throughout testing.	EIA-364-31B Method 3 Condition 7a
Thermal Shock5-55 to +10510 milliohm interface th		-55 to +105 degrees C. No evidence of mechanical damage. 10 milliohm maximum ΔR contact resistance per mated interface throughout testing.	EIA-364-32C Test Cond. VII	
Salt Spray	Salt Spray 5 % NaCl 48 hours. 10 milliohm maximum ∆R contact resistance mated interface throughout testing.		48 hours. 10 milliohm maximum ∆R contact resistance per mated interface throughout testing.	EIA-364-26B Test Cond. B

9. Test Sequence

9.1 Sequenced Tests	TEST	FLOW				
Test	Sequence Numbers for Test Group					
	Α	В	С	D	E	
Visual				1	1	
Low Level Connection Resistance (LLCR)	1,3,5	1,3,5,7	1,3	2,4,6	2,4,6	
Vibration				3		
Physical Shock				5		
Durability (with Environmental)		2			3	
Temperature Life (Thermal Aging)			2			
Humidity	4	6				
Thermal Shock	2	4				
Salt Spray					5	
Contact Wiper Normal Force			4			
Number of Samples (Connectors)	20	6	20	20	10	

9.2 Independent Tests

- 1. Contact Wiper Normal Force
- 2. Mating & Unmating Forces
- 3. Contact Retention
- 4. Contact Engagement & Separation
- 5. Cover Strain Relief Retention
- 6. Current Rating
- 7. Dielectric Withstanding Voltage
- 8. Insulation Resistance
- 9. Plating Thickness
- 10. Solderability
- 11. (Metal Coating) Adhesion

10. Figures











11. Agency Listings

11.1 Underwriters Laboratories (UL)

Agency	File No.
UL	E68080
CUL	E68080

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